

**Search Notes**

Application/Control No.

10/509,966

Examiner

TUAN A. PHAM

Applicant(s)/Patent under  
Reexamination

KANEKO, ICHIRO

Art Unit

2618

**SEARCHED**

Class	Subclass	Date	Examiner
455	63.1	11/25/2006	PHAM
	67.11		
	67.13		
	67.15		
	70		
	295		
	296		
375	346	11/27/2006	PHAM

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner
See interference search printout		11/27/2006	PHAM

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Consulted With: Nguyen Vo	11/27/2006	PHAM
Interference search	11/27/2006	PHAM